

STW26NM50

N-channel 500 V, 0.10 Ω 30 A TO-247 MDmesh™ Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} max	I _D
STW26NM50	500 V	< 0.12 Ω	30 A

- High dv/dt and avalanche capabilities
- Improved ESD capability
- Low input capacitance and gate charge

Application

■ Switching applications

Description

MDmesh[™] technology applies the benefits of the multiple drain process to STMicroelectronics' well-known PowerMESH[™] horizontal layout structure. The resulting product offers low onresistance, high dv/dt capability and excellent avalanche characteristics.

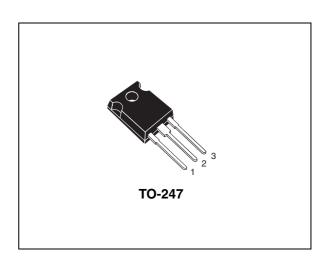


Figure 1. Internal schematic diagram

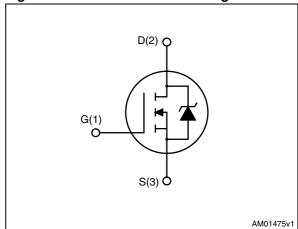


Table 1. Device summary

Order codes	Marking	Package	Packaging
STW26NM50	W26NM50	TO-247	Tube

Contents STW26NM50

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STW26NM50 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	500	V
V _{GS}	Gate-source voltage	±30	٧
I _D	Drain current (continuous) at T _C = 25 °C	30	Α
I _D	Drain current (continuous) at T _C = 100 °C	18.9	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	120	Α
P _{TOT}	Total dissipation at T _C = 25 °C	313	W
	Derating factor	2.5	W/°C
V _{ESD(G-S)}	Gate source ESD (HBM-C=100 pF, R=1.5 k Ω)	6000	V
dv/dt (2)	Peak diode recovery voltage slope	15	V/ns
T _{stg}	Storage temperature	-55 to 150	°C
Tj	Max. operating junction temperature	150	°C

^{1.} Pulse width limited by safe operating area

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	0.4	°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	62.5	°C/W
T _I	Maximum lead temperature for soldering purpose	300	°C

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_{j \text{ max}}$)	13	Α
E _{AS}	Single pulse avalanche energy (starting $T_J=25$ °C, $I_D=I_{AR}$, $V_{DD}=50$ V)	740	mJ

^{2.} $I_{SD} \leq$ 26 A, di/dt \leq 200 A/ μ s, $V_{DD} \leq$ $V_{(BR)DSS}$, $T_{J} \leq I_{JMAX}$

Electrical characteristics STW26NM50

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	500			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating V_{DS} = Max rating, T_{C} =125 °C			10 100	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			± 10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	٧
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 13 A		0.10	0.12	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	V _{DS} =15 V, I _D =13 A	-	20	-	S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer Capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0$	-	3000 700 50	-	pF pF pF
C _{oss eq.} (2)	Equivalent output capacitance	$V_{GS} = 0$, $V_{DS} = 0$ to 400 V	-	300	-	pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 400 V, I_{D} = 26 A, V_{GS} = 10 V, (see Figure 15)	-	76 20 36	-	nC nC nC

^{1.} Pulsed: pulse duration=300 μs, duty cycle 1.5%

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 250 \text{ V}, I_D = 13 \text{ A},$		28		ns
t _r	Rise time	$R_G = 4.7 \Omega, V_{GS} = 10 V,$		15	_	ns
t _{d(off)}	Turn-off-delay time	(see Figure 15)	-	13	-	ns
t _f	Fall time			19		ns

^{2.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS}

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)		-		26 104	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 26 A, V _{GS} = 0	-		1.5	V
t _{rr}	Reverse recovery time	$I_{SD} = 26 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		400		ns
Q_{rr}	Reverse recovery charge	V _{DD} = 100 V	-	5.5		μC
I _{RRM}	Reverse recovery current	(see Figure 16)		27.8		Α
t _{rr}	Reverse recovery time	$I_{SD} = 26 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		492		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}, T_j = 150 ^{\circ}\text{C}$	-	7		μC
I _{RRM}	Reverse recovery current	(see Figure 16)		28.8		Α

- 1. Pulse width limited by safe operating area
- 2. Pulsed: pulse duration = $300 \mu s$, duty cycle 1.5%

Table 9. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV _{GSO}	Gate-source breakdown voltage	lgs=± 1 mA (open drain)	30	-	-	٧

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

Electrical characteristics STW26NM50

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

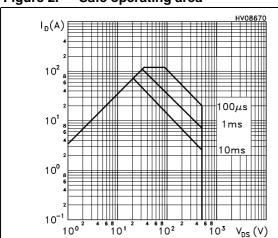


Figure 3. Thermal impedance

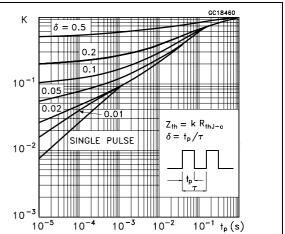


Figure 4. Output characteristics

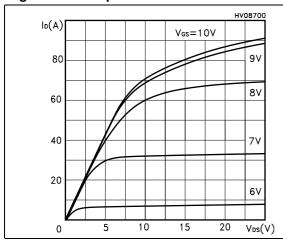


Figure 5. Transfer characteristics

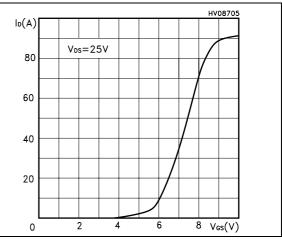


Figure 6. Transconductance

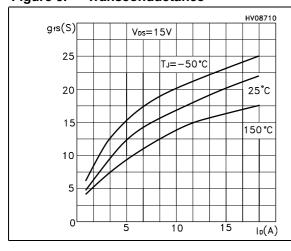


Figure 7. Static drain-source on resistance

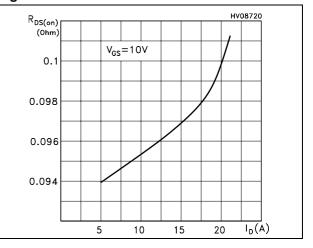


Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

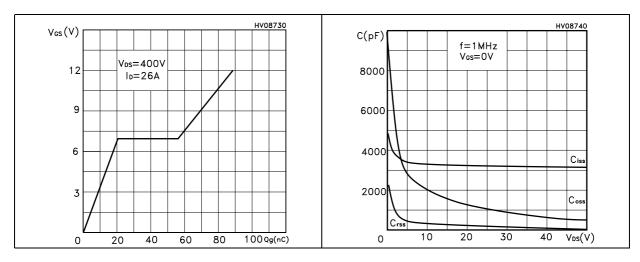


Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature temperature

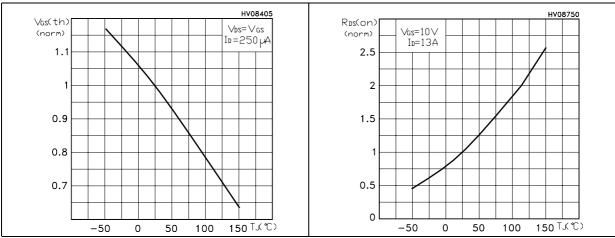
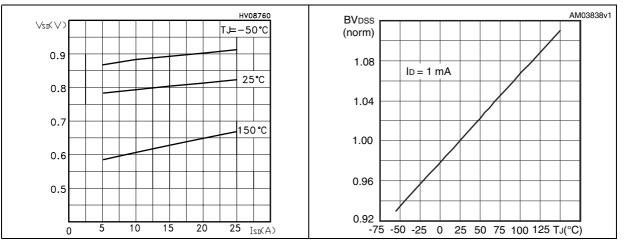


Figure 12. Source-drain diode forward characteristics

Figure 13. Normalized B_{VDSS} vs temperature



Test circuits STW26NM50

3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

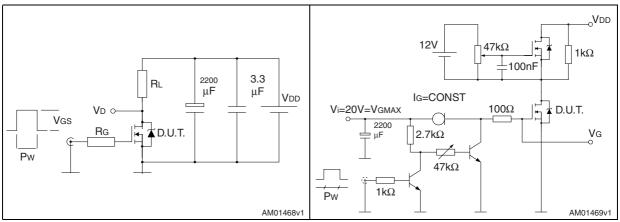


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

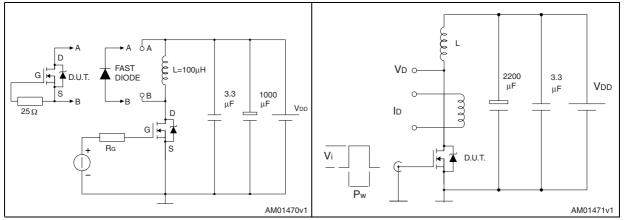
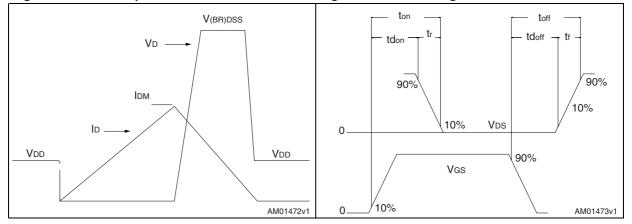


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform

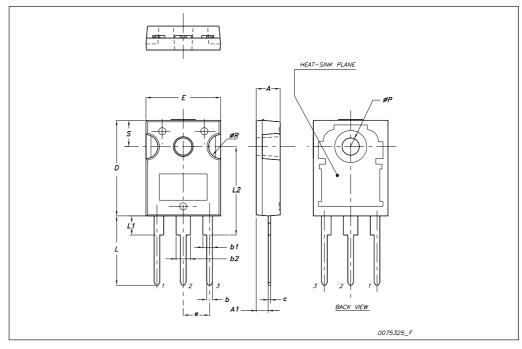


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

TO-247	mecha	nical	data
10-271		uuca	uata

Dim.	mm.		
	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
E	15.45		15.75
е		5.45	
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
øΡ	3.55		3.65
øR	4.50		5.50
S		5.50	



STW26NM50 Revision history

5 Revision history

Table 10. Document revision history

Date	Revision	Changes
24-Jun-2004	9	New stylesheet.
07-Feb-2005	10	I _D value changed
02-Oct-2009	11	Modified: test condition of V _{(BR)DSS} in <i>Table 5</i>

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